L Number	Hits	Search Text	DB	Time stamp
-	31	((verification or verif$3 or validation or valida$4) and (test near4 (vector$1 or pattern$1 or sequence$1 or list$1)) and (fault) and (((power adj suppl$3) near4 current$1) near$3 test$3)).ab.	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2003/10/28 17:55
-	1	((verification or verif$3 or validation or valida$4) and (test near4 (vector$1 or pattern$1 or sequence$1 or list$1)) and (fault) and (power adj suppl$3)).ab.	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2003/10/28 17:07
-	931	((verification or verif$3 or validation or valida$4) and (test near4 (vector$1 or pattern$1 or sequence$1 or list$1)) and (fault) and (power adj suppl$3))	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2003/10/28 17:07
-	30	(verification or verif$3 or validation or valida$4) and (test near4 (vector$1 or pattern$1 or sequence$1 or list$1)) and (fault) and ((power adj suppl$3) same (transient$1 and current$1 and test$3))	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2003/10/28 17:43
-	0	((fault adj (test$3 or simulat$4)) and (test near4 (vector$1 or pattern$1 or sequence$1 or list$1)) and (((power adj suppl$3) near4 current$1) near$3 (transient$2 or spike$1 or surge$1))).ab.	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2003/10/28 17:51
-	342	((fault adj (test$3 or simulat$4)) and (test near4 (vector$1 or pattern$1 or sequence$1 or list$1)) and (((power adj suppl$3) near4 current$1) near$3 (transient$2 or spike$1 or surge$1)))	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2003/10/28 17:59
-	259	(((fault adj (test$3 or simulat$4)) and (test near4 (vector$1 or pattern$1 or sequence$1 or list$1)) and (((power adj suppl$3) near4 current$1) near$3 (transient$2 or spike$1 or surge$1)))) and @ad<20000124	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2003/10/28 17:59
-	57	((((fault adj (test$3 or simulat$4)) and (test near4 (vector$1 or pattern$1 or sequence$1 or list$1)) and (((power adj suppl$3) near4 current$1) near$3 (transient$2 or spike$1 or surge$1)))) and @ad<20000124) and (logic adj signal$1)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2003/10/28 17:59
-	1	(((((fault adj (test$3 or simulat$4)) and (test near4 (vector$1 or pattern$1 or sequence$1 or list$1)) and (((power adj suppl$3) near4 current$1) near$3 (transient$2 or spike$1 or surge$1)))) and @ad<20000124) and (logic adj signal$1)) and (((power adj suppl$3) near4 current$1) near3 (transient$2 or spike$1 or surge$1))	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2003/10/28 17:58
-	7	((((((fault adj (test$3 or simulat$4)) and (test near4 (vector$1 or pattern$1 or sequence$1 or list$1)) and (((power adj suppl$3) near4 current$1) near$3 (transient$2 or spike$1 or surge$1)))) and @ad<20000124) and (logic adj signal$1)) and (((power adj suppl$3) same current$1) same (transient$2 or spike$1 or surge$1))	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2003/10/28 17:59
-	36	((fault adj (test$3 or simulat$4)) and (test near4 (vector$1 or pattern$1 or sequence$1 or list$1)) and (((power adj suppl$3) same current$1) same (transient$2 or spike$1 or surge$1)))	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2003/10/28 17:59
-	24	(((fault adj (test$3 or simulat$4)) and (test near4 (vector$1 or pattern$1 or sequence$1 or list$1)) and (((power adj suppl$3) same current$1) same (transient$2 or spike$1 or surge$1)))) and @ad<20000124	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2003/10/28 17:59

IEEE HOME I SEARCH IEEE I SHOP I WEB ACCOUNT I CONTACT IEEE

◆IEEE

Membership Publications/Services Standards Conferences Careers/Jobs

IEEE *Xplore*®
RELEASE 1.5

Welcome
United States Patent and Trademark Office

Help FAQ Terms · Quick Links ▽ » Advanced Search
IEEE Peer Review

Welcome to IEEE *Xplore*

○- Home
○- What Can
I Access?
○- Log-out

Tables of Contents

○- Journals
& Magazines
○- Conference
Proceedings
○- Standards

Search

○- By Author
○- Basic
○- Advanced

Member Services

○- Join IEEE
○- Establish IEEE
Web Account
○- Access the
IEEE Member
Digital Library

1) Enter a single keyword, phrase, or Boolean expression.
Example: acoustic imaging (means the phrase acoustic
imaging plus any stem variations)
2) Limit your search by using search operators and field
codes, if desired.

Example: optical (fiber fibre) ti

3) Limit the results by selecting Search Options.

4) Click Search. See Search Examples

```
((power <near/1> suppl*) <paragraph>
(current* <sentence> (transient* or spike*
or surge*)))<and>(((test <sentence>
(vector* or pattern* or sequence* or
test*))<and>(fault <near/1> (test* or
```

[Start Search] [Clear]

Note: This function returns plural and suffixed forms of the
keyword(s).

Search operators: More

Field codes: au (author), ti (title), ab (abstract), jn
(publication name), de (index term) More

Search Options:
Select publication types:
☑ IEEE Journals
☑ IEE Journals
☑ IEEE Conference proceedings
☑ IEE Conference proceedings
☑ IEEE Standards

Select years to search:
From year: [All ▼] to
[Present ▼]

Organize search results by:
Sort by: [Relevance ▼]
In: [Descending ▼] order
List [15 ▼] Results per page

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search
Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting No Robots Please |
Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

●

✦IEEE

Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE Xplore®
RELEASE 1.5

Welcome
United States Patent and Trademark Office

Help   FAQ   Terms   IEEE   Quick Links   » Search Results
Peer Review

Welcome to IEEE Xplore·

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

🖴 Print Format

Your search matched **1** of **981130** documents.

A maximum of **1** results are displayed, **15** to a page, sorted by **Relevance** in **descending** order.
You may refine your search by editing the current search expression or entering a new one the text box.

Then click **Search Again**.

((power <near/1> suppl*) <paragraph> (current* <sentence> (transient* or spike* or su

        Search Again

Results:
Journal or Magazine = **JNL**   Conference = **CNF**   Standard = **STD**

1 **A novel wavelet transform based transient current analysis for fault detection and localization**
Bhunia, S.; Roy, K.; Segura, J.;
Design Automation Conference, 2002. Proceedings. 39th , 10-14 June 2002
Page(s): 361 -366

[Abstract]   [PDF Full-Text (687 KB)] **IEEE CNF**

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search
Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting
No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

P☉RTAL

Try the *new* Portal design
Give us your opinion after using it.

Search Results

Search Results for: [(((power <near/1> suppl*) <paragraph> (current* <sentence> (transient* or spike* or surge*)))<AND>(((test <sentence> (vector* or pattern* or sequence* or list*))<AND>(fault <near/1> (test* or simulat*))))]
Found **2** of **122,228 searched.**

Search within Results

[   ] **GO**   > Advanced Search
> Search Help/Tips

Sort by: Title   Publication   Publication Date   Score   ❖Binder

---

Results 1 - 2 of 2   short listing

---

1   IC test using the energy consumption ratio   100%
Wanli Jiang , Bapiraju Vinnakota
Proceedings of the 36th ACM/IEEE conference on Design automation conference June 1999

2   Contest: a concurrent test generator for sequential circuits   100%
Vishwani D. Agrawal , Kwang-Ting Cheng , Prathima Agrawal
Proceedings of the 25th ACM/IEEE conference on Design automation June 1988
This paper describes the application of a concurrent fault simulator to automatic test vector generation. As faults are simulated in the fault simulator a cost function is simultaneously computed. A simple cost function is the distance (in terms of the number of gates and flip-flops) of a fault effect from a primary output. The input vector is then modified to reduce the cost function until a test is found. The paper presents experimental results showing the effectiveness of this method in ...

Results 1 - 2 of 2   short listing

P⊛RTAL
DIGITAL LIBRARY

US Patent & Trademark Office

Try the *new* Portal design
Give us your opinion after using it.

Search Results

Search Results for: [(test <sentence> (vector* or pattern* or sequence* or list*))<AND>(fault <near/1> (test* or simulat*))]
Found **738** of **122,228** searched.

Warning: Maximum result set of 200 exceeded. Consider refining.

Search within Results

[   ] **GO**   > Advanced Search
> Search Help/Tips

Sort by: Title   Publication   Publication Date   Score

Results 1 - 20 of 200   short listing

Prev Page   1 2 3 4 5 6 7 8 9 10 Next Page

---

1   A data acquisition methodology for on-chip repair of embedded memories   100%

Dirk Niggemeyer , Elizabeth M. Rudnick
ACM Transactions on Design Automation of Electronic Systems (TODAES) October 2003
Volume 8 Issue 4
Systems-on-Chips often contain a large amount of embedded memory. In order to obtain sufficiently high yield, efficient diagnosis and repair facilities are needed for the memories. A novel and efficient approach for collecting complete failure data during on-chip memory testing is proposed that can be combined with a row/column reconfiguration algorithm for complete on-chip memory repair. A sequence of diagnostic tests of linear order is utilized that detects and localizes all cells involved in ...

2   A circuit level fault model for resistive bridges   100%

Zhuo Li , Xiang Lu , Wangqi Qiu , Weiping Shi , D. M. H. Walker
ACM Transactions on Design Automation of Electronic Systems (TODAES) October 2003
Volume 8 Issue 4
Delay faults are an increasingly important test challenge. Modeling bridge faults as delay faults helps delay tests to detect more bridge faults. Traditional bridge fault models are incomplete because these models only model the logic faults or these models are not efficient to use in delay tests for large circuits. In this article, we propose a physically realistic yet economical resistive bridge fault model to model delay faults as well as logic faults. An accurate yet simple delay calculation ...

P🜨RTAL

Try the *new* Portal design
Give us your opinion after using it.

Search Results

Search Results for: **[(fault <near/1> (test* or simulat*))]**
Found **1,015** of **122,228 searched.**

Warning: Maximum result set of 200 exceeded. Consider refining.

Search within Results

Go   > Advanced Search
> Search Help/Tips

Sort by: <u>Title</u>   <u>Publication</u>   <u>Publication Date</u>   <u>Score</u>

Results 1 - 20 of 200   short listing

Prev Page   **1** <u>2</u> <u>3</u> <u>4</u> <u>5</u> <u>6</u> <u>7</u> <u>8</u> <u>9</u> <u>10</u> Next Page

---

1 <u>Verification of heuristic diagnostic knowledge by comparison with a causal/qualitative model</u>   100%
Graham F. Forsyth , Michael E. Larkin , Glen A. Wallace
Proceedings of the third international conference on Industrial and engineering applications of artificial intelligence and expert systems - Volume 2 June 1990
An approach to verify the knowledge base of a diagnostic expert system is described. An heuristic knowledge base collected from domain experts by interviews was analysed and the reasons for changes between versions were noted. The knowledge base was then compared with a small causal qualitative model of the device covered by the heuristic knowledge. Conclusions are drawn regarding the quality of the heuristic knowledge and indicate how it is planned to use the comparison of heuristic and ca ...

2 <u>Knowledge based fault management for OSI networks</u>   100%
Celia A. Joseph , A. Sherzer , K. Muralidhar
Proceedings of the third international conference on Industrial and engineering applications of artificial intelligence and expert systems - Volume 1 June 1990
The OSI Fault Management system (OSIFaM) is an evolving knowledge-based system for fault management of Open System Interconnection (OSI) networks. Our goal is to develop a knowledge-based tool that will reduce the expertise needed to recognize, diagnose and correct faults in OSI networks. For our first implementation, we are focusing on MAP 3.0 networks. This paper provides an overview of fault management in general, a brief survey of other fault management developments, the characteristics ...

3 <u>A data acquisition methodology for on-chip repair of embedded memories</u>   100%
Dirk Niggemeyer , Elizabeth M. Rudnick

◆IEEE

Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE Xplore®
RELEASE 1.4

Welcome
United States Patent and Trademark Office

Help FAQ Terms IEEE Quick Links   » Search Results
Peer Review

Welcome to IEEE Xplore

○ Home
○ What Can
   I Access?
○ Log-out

Tables of Contents

○ Journals
   & Magazines
○ Conference
   Proceedings
○ Standards

Search

○ By Author
○ Basic
○ Advanced

Member Services

○ Join IEEE
○ Establish IEEE
   Web Account
○ Access the
   IEEE Member
   Digital Library

🖨 Print Format

Your search matched **3** of **981130** documents.
Results are shown **15** to a page, sorted by **publication year** in **descending** order.

Results:
Journal or Magazine = **JNL**   Conference = **CNF**   Standard = **STD**

---

1 **An approach to dynamic power consumption current testing of CMOS ICs**
Segura, J.A.; Roca, M.; Mateo, D.; Rubio, A.;
VLSI Test Symposium, 1995. Proceedings., 13th IEEE , 30 April-3 May 1995
Page(s): 95 -100

[Abstract]   [PDF Full-Text (432 KB)] **IEEE CNF**

---

2 **GOS defects in SRAM: fault modeling and testing possibilities**
Segura, J.A.; Rubio, A.;
Memory Technology, Design and Testing, 1994., Records of the IEEE International Workshop on , 8-9 Aug. 1994
Page(s): 66 -71

[Abstract]   [PDF Full-Text (376 KB)] **IEEE CNF**

---

3 **CURRENT VS. LOGIC TESTING OF GATE OXIDE SHORT, FLOATING GATE AND BRIDGING FAILURES IN CMOS**
Rodriguez-Montanes, R.; Segura, J.A.; Champac, V.H.; Figueras, J.; Rubio, J.A.;
Test Conference, 1991, Proceedings., International , 26-30 Oct 1991
Page(s): 510
[Abstract]   [PDF Full-Text (700 KB)] **IEEE CNF**

Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE Xplore®
RELEASE 1.4

Welcome
United States Patent and Trademark Office

Help   FAQ   Terms   IEEE   Quick Links   » Search Results
Peer Review

Welcome to IEEE Xplore*

- ○ Home
- ○ What Can I Access?
- ○ Log-out

Tables of Contents

- ○ Journals & Magazines
- ○ Conference Proceedings
- ○ Standards

Search

- ○ By Author
- ○ Basic
- ○ Advanced

Member Services

- ○ Join IEEE
- ○ Establish IEEE Web Account
- ○ Access the IEEE Member Digital Library

🖶 Print Format

Your search matched **23** of **981130** documents.
Results are shown **15** to a page, sorted by **publication year** in **descending** order.

Results:
Journal or Magazine = **JNL**   Conference = **CNF**   Standard = **STD**

---

1 **New atpg algorithm for iddt-based testing**
Chehab, A.; Makki, R.; Maddali, R.;
Microelectronics, The 14th International Conference on 2002 - ICM ,
Dec. 11-13, 2002
Page(s): 224 -227

[Abstract]   [PDF Full-Text (237 KB)] **IEEE CNF**

---

2 I_{DDT} **testing of embedded CMOS SRAMs**
Kumar, S.A.; Makki, R.Z.; Binkley, D.M.;
Design, Automation and Test in Europe Conference and Exhibition,
2002. Proceedings , 4-8 March 2002
Page(s): 1117
[Abstract]   [PDF Full-Text (213 KB)] **IEEE CNF**

---

3 i_{DDT} **test methodologies for very deep sub-micron CMOS circuits**
Chehab, A.; Makki, R.; Spica, M.; Wu, D.;
Electronic Design, Test and Applications, 2002. Proceedings. The
First IEEE International Workshop on , 29-31 Jan. 2002
Page(s): 403 -407

[Abstract]   [PDF Full-Text (375 KB)] **IEEE CNF**

---

4 **SRAM test using on-chip dynamic power supply current sensor**
Jian Liu; Makki, R.Z.;
Memory Technology, Design and Testing, 1998. Proceedings.
International Workshop on , 24-25 Aug. 1998
Page(s): 57 -63

[Abstract]   [PDF Full-Text (56 KB)] **IEEE CNF**

---

5 **Testing Embedded Mem ries: Is Bist The Ultimate S luti n?
Testing Of Embedded Mem ries-the Aggregate**
Makki, R.Z.;

Test Symposium, 1998. ATS '98. Proceedings. Seventh Asian , 2-4
Dec. 1998
Page(s): 519 -519

[Abstract]   [PDF Full-Text (96 KB)] **IEEE CNF**

---

6 Dynamic power supply current testing of CMOS SRAMs
Jian Liu; Makki, R.Z.; Kayssi, A.;
Test Symposium, 1998. ATS '98. Proceedings. Seventh Asian , 2-4
Dec. 1998
Page(s): 348 -353

[Abstract]   [PDF Full-Text (52 KB)] **IEEE CNF**

---

7 A high level language implementation of a general purpose telemetry system for biomedical applications
Rorie, J.F.; Simmerman, J.K.; Makki, R.Z.; Piendl, R.D.;
System Theory, 1996., Proceedings of the Twenty-Eighth
Southeastern Symposium on , 31 March-2 April 1996
Page(s): 338 -342

[Abstract]   [PDF Full-Text (564 KB)] **IEEE CNF**

---

8 Transient power supply current testing of digital CMOS circuits
Makki, R.Z.; Shyang-Tai Su; Nagle, T.;
Test Conference, 1995. Proceedings., International , 21-25 Oct. 1995

Page(s): 892 -901

[Abstract]   [PDF Full-Text (864 KB)] **IEEE CNF**

---

9 Power supply current detectability of SRAM defects
Jian Liu; Makki, R.;
Test Symposium, 1995., Proceedings of the Fourth Asian , 23-24
Nov. 1995
Page(s): 367 -373

[Abstract]   [PDF Full-Text (496 KB)] **IEEE CNF**

---

10 Dynamic power supply current monitoring of SRAMs
Shyang-Tai Su; Makki, R.Z.; Nagle, H.T.; Jian Liu;
ASIC Conference and Exhibit, 1994. Proceedings., Seventh Annual
IEEE International , 19-23 Sept. 1994
Page(s): 370 -373

[Abstract]   [PDF Full-Text (336 KB)] **IEEE CNF**

---

11 A testable static RAM structure f r efficient c verage f

pattern sensitive faults
Shyang-Tai Su; Makki, R.Z.;
VLSI Test Symposium, 1992. '10th Anniversary. Design, Test and
Application: ASICs and Systems-on-a-Chip', Digest of Papers., 1992
IEEE , 7-9 April 1992
Page(s): 229 -234

[Abstract] [PDF Full-Text (360 KB)] **IEEE CNF**

---

12 ON THE INTEGRATION OF DESIGN AND MANUFACTURING FOR IMPROVED TESTABILITY

Makki, R.Z.; Daneshvar, K.; Tranjan, F.; Greene, R.;
Test Conference, 1991, Proceedings., International , 26-30 Oct 1991
Page(s): 248
[Abstract] [PDF Full-Text (488 KB)] **IEEE CNF**

---

13 On controllability estimation to aid in partitioning logic circuits

Sern, J.; Makki, R.;
Southeastcon '91., IEEE Proceedings of , 7-10 April 1991
Page(s): 1074 -1077 vol.2

[Abstract] [PDF Full-Text (296 KB)] **IEEE CNF**

---

14 NEPTUNE: an automatic test pattern generator for finite state machines

Divekar, S.; Makki, R.Z.; Mostafavi, T.M.;
Southeastcon '91., IEEE Proceedings of , 7-10 April 1991
Page(s): 1060 -1064 vol.2

[Abstract] [PDF Full-Text (440 KB)] **IEEE CNF**

---

15 A VLSI based logic analyzer interface for a microprocessor development system

Lee, B.H.; Makki, R.Z.; Rohe, C.;
System Theory, 1991. Proceedings., Twenty-Third Southeastern
Symposium on , 10-12 March 1991
Page(s): 101 -105

[Abstract] [PDF Full-Text (400 KB)] **IEEE CNF**

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search
Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting
No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

◈IEEE

Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE *Xplore*®
RELEASE 1.5

Welcome
United States Patent and Trademark Office

Help   FAQ   Terms   IEEE   Quick Links   ▽   » Author Search
Peer Review

Welcome to IEEE *Xplore*®

O— Home
O— What Can
     I Access?
O— Log-out

Tables of Contents

O— Journals
     & Magazines
O— Conference
     Proceedings
O— Standards

Search

O— By Author
O— Basic
O— Advanced

Member Services

O— Join IEEE
O— Establish IEEE
     Web Account
O— Access the
     IEEE Member
     Digital Library

Quick Find an Author:

Enter a last name to quickly locate articles by that author.

[   ]

[   ]   Go

Note: You may enter a partial name if your are unsure of the spelling.
OR
Select a letter to browse the author list

A B C D E F G H I J K L M N O P Q R S T U V W X Y Z | ALL

No Authors Found with beginning letter: beasely

A B C D E F G H I J K L M N O P Q R S T U V W X Y Z | ALL

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced
Search
Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email
Alerting No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE Xplore®
RELEASE 1.4

Welcome
United States Patent and Trademark Office

Help   FAQ   Terms   IEEE   Quick Links   » Search Results
Peer Review

Welcome to IEEE Xplore*

O- Home
O- What Can
    I Access?
O- Log-out

Tables of Contents

O- Journals
    & Magazines
O- Conference
    Proceedings
O- Standards

Search

O- By Author
O- Basic
O- Advanced

Member Services

O- Join IEEE
O- Establish IEEE
    Web Account
O- Access the
    IEEE Member
    Digital Library

🖶 Print Format

Your search matched **3** of **981130** documents.
Results are shown **15** to a page, sorted by **publication year** in **descending** order.

Results:
Journal or Magazine = **JNL**   Conference = **CNF**   Standard = **STD**

---

1 **A grouping scheme for reliable multicast congestion control**
Ramamurthy, H.; Karandikar, A.; Verma, R.;
Communication Systems, 2002. ICCS 2002. The 8th International
Conference on , Volume: 2 , 25-28 Nov. 2002
Page(s): 938 -942 vol.2

[Abstract]   [PDF Full-Text (430 KB)] **IEEE CNF**

---

2 I_{DD} **pulse response testing on analog and digital CMOS circuits**
Beasley, J.S.; Ramamurthy, H.; Ramirez-Angulo, J.; DeYong, M.;
Test Conference, 1993. Proceedings., International , 17-21 Oct. 1993

Page(s): 626 -634

[Abstract]   [PDF Full-Text (480 KB)] **IEEE CNF**

---

3 i_{DD} **pulse response testing: a unified approach to testing digital and analogue ICs**
Beasley, J.; Ramamurthy, H.; Ramirez-Angulo, J.; Deyong, M.;
Electronics Letters , Volume: 29 Issue: 24 , 25 Nov. 1993
Page(s): 2101 -2103

[Abstract]   [PDF Full-Text (232 KB)] **IEE JNL**

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search
Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting
No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE *Xplore*®
RELEASE 1.5

Welcome
United States Patent and Trademark Office

Help   FAQ   Terms   IEEE   Quick Links

» Search Results

Peer Review

Welcome to IEEE *Xplore*®

- ○ Home
- ○ What Can
  I Access?
- ○ Log-out

Tables of Contents

- ○ Journals
  & Magazines
- ○ Conference
  Proceedings
- ○ Standards

Search

- ○ By Author
- ○ Basic
- ○ Advanced

Member Services

- ○ Join IEEE
- ○ Establish IEEE
  Web Account
- ○ Access the
  IEEE Member
  Digital Library

🖴 Print Format

Your search matched **62** of **981130** documents.

A maximum of **62** results are displayed, **25** to a page, sorted by **Relevance** in **descending** order.
You may refine your search by editing the current search expression or entering a new one the text box.
Then click **Search Again.**

| ((power <near/1> suppl*) <paragraph> (current* <sentence> (transient* or spike* or su |

| Search Again |

Results:
Journal or Magazine = **JNL**   Conference = **CNF**   Standard = **STD**

1 **A novel built-in dynamic supply current monitor for mixed IC testing**
Arguelles, J.; Lopez, M.J.;
Testing Mixed Signal Circuits and Systems (Ref. No: 1997/361), IEE Colloquium on , 23 Oct. 1997
Page(s): 12/1 -12/4

[Abstract]   [PDF Full-Text (312 KB)] **IEE CNF**

2 **Examinations of ZnO-varistors in the leakage region with regard to high frequency stresses**
Bak-Jensen, J.; Bak-Jensen, B.; Damsgaard Mikkelsen, S.; Sorensen, J.T.;
Power Electronics and Applications, 1993., Fifth European Conference on , 13-16 Sep 1993
Page(s): 191 -196 vol.8

[Abstract]   [PDF Full-Text (320 KB)] **IEE CNF**

3 **Bi-polarity phase-shifted controlled voltage mode AC/AC converters with high frequency AC link**
Daolian Chen; Lei Li;
Power Electronics Specialist, 2003. PESC '03. IEEE 34th Annual Conference on , Volume: 2 , 15-19 June 2003
Page(s): 677 -682 vol.2

[Abstract]   [PDF Full-Text (471 KB)] **IEEE CNF**

4 CMOS IC stuck- pen-fault electrical effects and design c nsiderati ns

Soden, J.M.; Treece, R.K.; Taylor, M.R.; Hawkins, C.F.;
Test Conference, 1989. Proceedings. 'Meeting the Tests of Time'.,
International , 29-31 Aug. 1989
Page(s): 423 -430

[Abstract]   [PDF Full-Text (624 KB)] **IEEE CNF**

5 Performance analysis and signal processing in a current sensing power MOSFET (SENSEFET)

Yuvarajan, S.; Wang, L.;
Industry Applications Society Annual Meeting, 1991., Conference
Record of the 1991 IEEE , 28 Sept.-4 Oct. 1991
Page(s): 1445 -1450 vol.2

[Abstract]   [PDF Full-Text (272 KB)] **IEEE CNF**

6 A novel high efficiency UPS using improved inverter and DC to DC converter

Eishima, Y.; Jinno, M.; Tominaga, F.; Sakamoto, H.; Harada, K.;
Telecommunications Energy Conference, 1991. INTELEC '91., 13th
International , 5-8 Nov. 1991
Page(s): 595 -600

[Abstract]   [PDF Full-Text (320 KB)] **IEEE CNF**

7 Design and testing of power supplies for the high power gyrotron

*Tsuneoka, M.; Fujita, H.; Nagashima, T.; Cho, Y.; Yamane, T.;
Hayakawa, S.; Ohtsuka, S.; Harada, K.; Yoshida, T.; Shibuya, T.;
Ishibashi, M.;*
Fusion Engineering, 1991. Proceedings., 14th IEEE/NPSS Symposium
on , 30 Sept.-3 Oct. 1991
Page(s): 497 -500 vol.1

[Abstract]   [PDF Full-Text (260 KB)] **IEEE CNF**

8 Groundbounce in ASIC's: model and test results

Diaz-Olavarrieta, L.;
Electromagnetic Compatibility, 1991. Symposium Record. IEEE 1991
International Symposium on , 12-16 Aug. 1991
Page(s): 387 -392

[Abstract]   [PDF Full-Text (576 KB)] **IEEE CNF**

9 **Test generati n and fault detecti n techniques in mixed circuits**
Bracho, S.; Martinez, M.; Arguelles, J.;
Circuits and Systems, 1992., Proceedings of the 35th Midwest
Symposium on , 9-12 Aug. 1992
Page(s): 931 -937 vol.2

[Abstract]   [PDF Full-Text (440 KB)] **IEEE CNF**

10 **Design of an electric power interface compatibility 200 kVa mobile test facility**
Williams, S.; Sityar, I.; Rager, P.; Reitweisner, J.;
Industry Applications Society Annual Meeting, 1992., Conference
Record of the 1992 IEEE , 4-9 Oct. 1992
Page(s): 1322 -1326 vol.2

[Abstract]   [PDF Full-Text (320 KB)] **IEEE CNF**

11 **Management of high current transients in the CWDD injector 200 kV power system**
Carwardine, J.A.; Pile, G.; Zinneman, T.E.;
Particle Accelerator Conference, 1993., Proceedings of the 1993 ,
17-20 May 1993
Page(s): 3210 -3212 vol.4

[Abstract]   [PDF Full-Text (240 KB)] **IEEE CNF**

12 **A high power water cooled resistor for the high voltage power supply in the TRIUMF RF system**
Jensen, K.; Blaker, G.; Kuramoto, R.;
Particle Accelerator Conference, 1993., Proceedings of the 1993 ,
17-20 May 1993
Page(s): 1300 -1302 vol.2

[Abstract]   [PDF Full-Text (260 KB)] **IEEE CNF**

13 **Filament power supply improvement of the TRIUMF RF system**
Mitra, A.K.; Lu, J.J.;
Particle Accelerator Conference, 1993., Proceedings of the 1993 ,
17-20 May 1993
Page(s): 1303 -1305 vol.2

[Abstract]   [PDF Full-Text (212 KB)] **IEEE CNF**

14 I_{DD} pulse resp nse testing n anal g and digital CMOS circuits
Beasley, J.S.; Ramamurthy, H.; Ramirez-Angulo, J.; DeYong, M.;
Test Conference, 1993. Proceedings., International , 17-21 Oct. 1993

Page(s): 626 -634

[Abstract]   [PDF Full-Text (480 KB)] **IEEE CNF**

15 **Modeling the effect of ground bounce on noise margin**
Haydt, M.S.; Owens, R.; Mourad, S.;
Test Conference, 1994. Proceedings., International , 2-6 Oct. 1994
Page(s): 279 -285

[Abstract]   [PDF Full-Text (420 KB)] **IEEE CNF**

16 **An off-chip IDDq current measurement unit for telecommunication ASICs**
Manhaeve, H.A.R.; Wrighton, P.L.; van Sas, J.; Swerts, U.;
Test Conference, 1994. Proceedings., International , 2-6 Oct. 1994
Page(s): 203 -212

[Abstract]   [PDF Full-Text (784 KB)] **IEEE CNF**

17 **A new parallel processing UPS with the performance of harmonic suppression and reactive power compensation**
Hurng-Liahng Jou; Jinn-Chang Wu;
Power Electronics Specialists Conference, PESC '94 Record., 25th Annual IEEE , 20-25 June 1994
Page(s): 1443 -1450 vol.2

[Abstract]   [PDF Full-Text (540 KB)] **IEEE CNF**

18 **Dynamic power supply current monitoring of SRAMs**
Shyang-Tai Su; Makki, R.Z.; Nagle, H.T.; Jian Liu;
ASIC Conference and Exhibit, 1994. Proceedings., Seventh Annual IEEE International , 19-23 Sept. 1994
Page(s): 370 -373

[Abstract]   [PDF Full-Text (336 KB)] **IEEE CNF**

19 **Fuzzy l gic pr tecti n circuit pr vides a flexible resp nse in severe transient envir nments**
Grill, T.F.; Roy, B.P.; Worden, J.A.;

WESCON/94. 'Idea/Microelectronics'. Conference Record , 27-29
Sept. 1994
Page(s): 103 -109

[Abstract]   [PDF Full-Text (524 KB)] **IEEE CNF**

20 Interface specifications for a global grounding topology
Ashdown, B.; Korbel, N.; Panesar, B.;
Telecommunications Energy Conference, 1994. INTELEC '94., 16th
International , 30 Oct.-3 Nov. 1994
Page(s): 400 -406

[Abstract]   [PDF Full-Text (456 KB)] **IEEE CNF**

21 Transient power supply current testing of digital CMOS circuits
Makki, R.Z.; Shyang-Tai Su; Nagle, T.;
Test Conference, 1995. Proceedings., International , 21-25 Oct. 1995

Page(s): 892 -901

[Abstract]   [PDF Full-Text (864 KB)] **IEEE CNF**

22 An approach to dynamic power consumption current testing of CMOS ICs
Segura, J.A.; Roca, M.; Mateo, D.; Rubio, A.;
VLSI Test Symposium, 1995. Proceedings., 13th IEEE , 30 April-3
May 1995
Page(s): 95 -100

[Abstract]   [PDF Full-Text (432 KB)] **IEEE CNF**

23 Current test methods in mixed signal circuits
Bracho, S.; Martinez, M.; Arguelles, J.;
Circuits and Systems, 1995., Proceedings., Proceedings of the 38th
Midwest Symposium on , Volume: 2 , 13-16 Aug. 1995
Page(s): 1162 -1167 vol.2

[Abstract]   [PDF Full-Text (524 KB)] **IEEE CNF**

24 An i_{DD} transient analysis technique f r defect detecti n in digital integrated circuits
Beasley, J.; Ramirez-Angulo, J.; Steiner, R.;
Circuits and Systems, 1995., Proceedings., Proceedings of the 38th

Midwest Symposium on , Volume: 1 , 13-16 Aug. 1995
Page(s): 286 -289 vol.1

[Abstract]   [PDF Full-Text (280 KB)] **IEEE CNF**

25 **Power supply current detectability of SRAM defects**
Jian Liu; Makki, R.;
Test Symposium, 1995., Proceedings of the Fourth Asian , 23-24
Nov. 1995
Page(s): 367 -373

[Abstract]   [PDF Full-Text (496 KB)] **IEEE CNF**

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search
Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting
No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

IEEE

Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE *Xplore®*
RELEASE 1.4

Welcome
United States Patent and Trademark Office

Help   FAQ   Terms   IEEE   Quick Links   » Search Results
Peer Review

Welcome to IEEE *Xplore*

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

Print Format

Your search matched **7** of **981130** documents.
Results are shown **15** to a page, sorted by **publication year** in **descending** order.

Results:
Journal or Magazine = **JNL**   Conference = **CNF**   Standard = **STD**

---

1 **Defect detection using power supply transient signal analysis**
Germida, A.; Zheng Yan; Plusquellic, J.F.; Muradali, F.;
Test Conference, 1999. Proceedings. International , 28-30 Sept. 1999
Page(s): 67 -76

[Abstract]   [PDF Full-Text (916 KB)] **IEEE CNF**

---

2 **8-bit multiplier simulation experiments investigating the use of power supply transient signals for the detection of CMOS defects**
Plusquellic, J.F.; Germida, A.; Yan, Z.;
Defect and Fault Tolerance in VLSI Systems, 1999. DFT '99. International Symposium on , 1-3 Nov. 1999
Page(s): 68 -76

[Abstract]   [PDF Full-Text (160 KB)] **IEEE CNF**

---

3 **Time- and frequency-domain transient signal analysis for defect detection in CMOS digital ICs**
Plusquellic, J.F.; Chiarulli, D.M.; Levitan, S.P.;
Circuits and Systems I: Fundamental Theory and Applications, IEEE Transactions on , Volume: 46 Issue: 11 , Nov. 1999
Page(s): 1390 -1394

[Abstract]   [PDF Full-Text (152 KB)] **IEEE JNL**

---

4 **An automated technique to identify defective CMOS devices based on linear regression analysis of transient signal data**
Plusquellic, J.F.; Chiarulli, D.M.; Levitan, S.P.;
IDDQ Testing, 1998. Proceedings. 1998 IEEE International Workshop on , November 12-13, 1998
Page(s): 32 -36

[Abstract]   [PDF Full-Text (152 KB)] **IEEE CNF**

---

5 Identificati n f defective CMOS devices using c rrelati n and regressi n analysis f frequency d main transient signal data
Plusquellic, J.F.; Chiarulli, D.M.; Levitan, S.P.;
Test Conference, 1997. Proceedings., International , 1-6 Nov. 1997
Page(s): 40 -49

[Abstract]   [PDF Full-Text (1112 KB)] **IEEE CNF**

---

6 Digital integrated circuit testing using transient signal analysis
Plusquellic, J.F.; Chiarulli, D.M.; Levitan, S.P.;
Test Conference, 1996. Proceedings., International , 20-25 Oct. 1996

Page(s): 481 -490

[Abstract]   [PDF Full-Text (1024 KB)] **IEEE CNF**

---

7 Digital IC device testing by transient signal analysis (TSA)
Plusquellic, J.F.; Chiarulli, D.M.; Levitan, S.P.;
Electronics Letters , Volume: 31 Issue: 18 , 31 Aug. 1995
Page(s): 1568 -1570

[Abstract]   [PDF Full-Text (276 KB)] **IEE JNL**

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search
Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting
No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

ACM Digital Library

Try the *new* Portal design
Give us your opinion after using it.

Search Results

Search Results for: **[Shyang-Tai and Su]**
Found **4** of **122,228 searched.**

Search within Results

|_____| **Go**   > Advanced Search
> Search Help/Tips

Sort by: Title   Publication   Publication Date   Score   ◆Binder

---

Results 1 - 4 of 4   short listing

---

1   Session 7A: Manufacturing test: stuck-at to crosstalk: Crosstalk fault detection by dynamic Idd   77%
   Xiaoyun Sun , Seonki Kim , Bapiraju Vinnakota
   Proceedings of the 2001 IEEE/ACM international conference on Computer-aided design
   November 2001
   Undesired capacitive crosstalk between signals is expected to be a significant concern in deep
submicron circuits. New test techniques are needed for these crosstalk faults since they may
cause unacceptable performance degradation. We analyze the impact of crosstalk faults on a
circuit's power dissipation. Crosstalk faults can be detected by monitoring the dynamic supply
current. The test method is based on a recently developed dynamic Idd test metric, the energy
consumption ratio (ECR). ECR-bas ...

2   New test methods targeting non-classical faults: A novel wavelet transform based transient   77%
   current analysis for fault detection and localization
   Swarup Bhunia , Kaushik Roy , Jaume Segura
   Proceedings of the 39th conference on Design automation June 2002
   Transient current (IDD) based testing has been often cited and investigated as an alternative
and/or supplement to quiescent current (IDDQ) testing. While the potential of IDD testing for
fault detection has been established, there is no known efficient method for fault diagnosis
using IDD analysis. In this paper, we present a novel integrated method for fault detection and
localization using wavelet transform based IDD waveform analysis. The time-frequency
resolution property of wavelet transfo ...

3   Deep submicron defect detection with the energy consumption ratio   77%
   Bapiraju Vinnakota
   Proceedings of the 1999 IEEE/ACM international conference on Computer-aided design
   November 1999

4   IC test using the energy consumption ratio   77%
   Wanli Jiang , Bapiraju Vinnakota

Proceedings of the 36th ACM/IEEE conference on Design automation conference June 1999

Results 1 - 4 of 4   <u>short listing</u>